


<b>Search Notes</b> 	<b>Application/Control No.</b> 10534423	<b>Applicant(s)/Patent Under Reexamination</b> HAYASHI ET AL.
	<b>Examiner</b> Christopher R Lea	<b>Art Unit</b> 4161

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
PLUS Search (already in IFW)	10/10/08	/CRL/
Text Search of Patente Literature (See EAST Search History)	10/10/08	/CRL/
Inventor Name Seach	10/10/08	/CRL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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